

<b>Notice of References Cited</b>	Application/Control No. 10/538,022	Applicant(s)/Patent Under Reexamination OKAMOTO ET AL.	
	Examiner Tarek Chbouki	Art Unit 2169	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,330,670 B1	12-2001	England et al.	713/2
*	B	US-2003/0061165 A1	03-2003	Okamoto et al.	705/52
*	C	US-6,697,824 B1	02-2004	Bowman-Amuah, Michel K.	709/229
*	D	US-2004/0070602 A1	04-2004	Kobuya et al.	345/738
*	E	US-2004/0143661 A1	07-2004	Higashi et al.	709/224
*	F	US-2004/0162846 A1	08-2004	Nakahara et al.	707/102
*	G	US-2004/0230797 A1	11-2004	Ofek et al.	713/168
*	H	US-2004/0249759 A1	12-2004	Higashi et al.	705/059
*	I	US-2005/0060334 A1	03-2005	Kawamoto et al.	707/102
*	J	US-2005/0234860 A1	10-2005	Roever et al.	707/001
*	K	US-7,103,663 B2	09-2006	Inoue et al.	709/225
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.